IN THE CLAIMS

 (Currently Amended) For use with an integrated circuit (IC) having a testing port, a system for securing said IC as against subsequent reprogramming, comprising:

port inhibit circuitry located on said IC and modifiable to achieve a configuration that determines an extent to which said testing port is enabled, said extent selected from the group consisting of:

fully enabled,

only partially disabled, and

completely disabled; and

port access circuitry, coupled to said testing port, that enables said testing port based on said configuration.

- (Original) The system as recited in Claim 1 wherein said testing port is a Joint Test Action Group (JTAG) port.
- (Original) The system as recited in Claim 1 wherein said port inhibit circuitry comprises an inhibit bit in a one-time programmable register.
- (Original) The system as recited in Claim 1 wherein said port inhibit circuitry is configured to be permanently modified prior to delivering said IC to a user thereof.

Canceled

Appl. No. 10/706,365 Reply to Examiner's Action dated 11/09/2007

(Original) The system as recited in Claim 1 wherein said testing port comprises a

direct loopback between input and output pins thereof.

(Original) The system as recited in Claim 1 wherein said IC is a baseband chip of a

mobile communication device.

(Previously Presented) For use with an integrated circuit (IC) having a testing port, a

method of securing said IC as against subsequent reprogramming, comprising:

modifying port inhibit circuitry located on said IC to achieve a configuration that determines

an extent to which said testing port is enabled, said extent selected from a group consisting of:

fully enabled,

only partially disabled, and

completely disabled; and

enabling said testing port based on said configuration.

(Original) The method as recited in Claim 8 wherein said testing port is a Joint Test

Action Group (JTAG) port.

10. (Original) The method as recited in Claim 8 wherein said port inhibit circuitry

comprises an inhibit bit in a one-time programmable register.

11. (Original) The method as recited in Claim 8 wherein said modifying comprises

permanently modifying said port inhibit circuitry prior to delivering said IC to a user thereof.

Canceled

13. (Original) The method as recited in Claim 8 wherein said testing port comprises a

direct loopback between input and output pins thereof.

14. (Original) The method as recited in Claim 8 wherein said IC is a baseband chip of a

mobile communication device.

15. (Currently Amended) An electronic device, comprising:

an integrated circuit (IC), including:

a testing port,

port inhibit circuitry located on said IC and modifiable to achieve a configuration that

determines an extent to which said testing port is enabled, said extent selected from the group

consisting:

fully enabled,

only partially disabled, and

completely disabled; and

port access circuitry, coupled to said testing port, that enables said testing port based on said

configuration.

Appl. No. 10/706,365 Reply to Examiner's Action dated 11/09/2007

16. (Original) The electronic device as recited in Claim 15 wherein said testing port is a

Joint Test Action Group (JTAG) port.

17. (Original) The electronic device as recited in Claim 15 wherein said port inhibit

circuitry comprises an inhibit bit in a one-time programmable register.

18. (Original) The electronic device as recited in Claim 15 wherein said port inhibit

circuitry is configured to be permanently modified prior to delivering said IC to a user thereof.

Canceled

20. (Original) The electronic device as recited in Claim 15 wherein said electronic device

is selected from the group consisting of:

a mobile telephone,

a PDA.

an MDA.

an MP3 player, and

a set-top box.